

TSL2591 Datasheet - Apr. 2013 - ams163.5

General Description

The TSL2591 is a very-high sensitivity light-to-digital converter that transforms light intensity into a digital signal output capable of direct I²C interface. The device combines one broadband photodiode (visible plus infrared) and one infrared-responding photodiode on a single CMOS integrated circuit. Two integrating ADCs convert the photodiode currents into a digital output that represents the irradiance measured on each channel. This digital output can be input to a microprocessor where illuminance (ambient light level) in lux is derived using an empirical formula to approximate the human eye response. The TSL2591 supports a traditional level style interrupt that remains asserted until the firmware clears it.

Figure TSL2591 – 1: Key Benefits and Features

Benefits	Features
Approximates Human Eye Response	Dual Diode
Flexible Operation	Programmable Analog Gain and Integration Time
Suited for Operation Behind Dark Glass	600M:1 Dynamic Range
Low Operating Overhead	 Two Internal Interrupt Sources Programmable Upper and Lower Thresholds One Interrupt Includes Programmable Persistence Filter
Low Power 3.0 µA Sleep State	User Selectable Sleep Mode
I ² C Fast Mode Compatible Interface	 Data Rates up to 400 kbit/s Input Voltage Levels Compatible with 3.0V Bus



Figure TSL2591 – 2: Block Diagram



Detailed Description

The TSL2591 contains two integrating analog-to-digital converters (ADC) that integrate currents from two photodiodes. Integration of both channels occurs simultaneously. Upon completion of the conversion cycle, the conversion result is transferred to the Channel 0 and Channel 1 data registers, respectively. The transfers are double-buffered to ensure that the integrity of the data is maintained. After the transfer, the device automatically begins the next integration cycle.

Communication with the device is accomplished through a standard, two-wire l²C serial bus. Consequently, the TSL2591 can be easily connected to a microcontroller or embedded controller. No external circuitry is required for signal conditioning. Because the output of the device is digital, the output is effectively immune to noise when compared to an analog signal.

The TSL2591 also supports an interrupt feature that simplifies and improves system efficiency by eliminating the need to poll a sensor for a light intensity value. The primary purpose of the interrupt function is to detect a meaningful change in light intensity. The concept of a meaningful change can be defined by the user both in terms of light intensity and time, or persistence, of that change in intensity. The device has the ability to define two sets of thresholds, both above and below the current light level. An interrupt is generated when the value of a conversion exceeds either of these limits. One set of thresholds can be configured to trigger an interrupt only when the ambient light exceeds them for a configurable amount of time (persistence) while the other set can be configured to trigger an immediate interrupt.



Pin Assignment

The TSL2591 pin assignments are described below.

Figure TSL2591 – 3: Pin Diagram

Package FN Dual Flat No-Lead (Top View): Package drawing is not to scale.



Figure TSL2591 – 4: Pin Description

Pin Number	Pin Name	Description
1	SCL	I ² C serial clock input terminal
2	INT	Interrupt — open drain output (active low).
3	GND	Power supply ground. All voltages are referenced to GND.
4	NC	No connect — do not connect.
5	V _{DD}	Supply voltage
6	SDA	I ² C serial data I/O terminal



Ordering Information

Figure TSL2591 – 5: Ordering Information

Ordering Code	Address	Interface	Delivery form	
TSL25911FN	0x29	$I^2 C V_{bus} = V_{DD}$ Interface	ODFN-6	
TSL25913FN*	0x29	$I^2 C V_{bus} = 1.8 V$	ODFN-6	

*Contact factory for availability.

Notes:

- 1. All products are RoHS compliant and ams green.
- 2. Buy our products or get free samples online at <u>www.ams.com/ICdirect</u>
- 3. Technical Support is available at www.ams.com/Technical-Support
- 4. For further information and requests, email us at $\underline{sales@ams.com}$
- 5. (or) find your local distributor at <u>www.ams.com/distributor</u>
- 6. Please contact ams for alternate address device availability.

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only. Functional operation of the device at these or any other conditions beyond those indicated under "Operating Conditions" is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Figure TSL2591 – 6: Absolute Maximum Ratings

Parameter	Min	Max	Units	Comments
Supply voltage, V _{DD}		3.8	V	All voltages are with respect to GND
Input terminal voltage	-0.5	3.8	V	
Output terminal voltage	-0.5	3.8	V	
Output terminal current	-1	20	mA	
Storage temperature range, T _{stg}	-40	85	°C	
ESD tolerance, human body model		2000	V	



Electrical Characteristics

All limits are guaranteed. The parameters with min and max values are guaranteed with production tests or SQC (Statistical Quality Control) methods.

Figure TSL2591 – 7: Recommended Operating Conditions

Symbol	Parameter	Min	Тур	Мах	Units
V _{DD}	Supply voltage	2.7	3	3.6	V
T _A	Operating free-air temperature	-30		70	°C

Figure TSL2591 – 8:

Operating Characteristics, V_{DD}=3V, T_A=25°C (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
I _{DD}	Supply Current	Active Sleep state - no I ² C activity		275 2.3	325 4	μΑ
V _{OL}	INT, SDA output low voltage	3mA sink current 6mA sink current	0 0		0.4 0.6	V
I _{LEAK}	Leakage current, SDA, SCL, INT pins		-5		5	μΑ
V _{IH}	SCL, SDA input high voltage		0.7 V _{DD}			V
V _{IL}	SCL, SDA input low voltage				0.3 V _{DD}	V



Figure TSL2591 – 9:

ALS Characteristics, V_{DD} =3V, T_A =25°C, AGAIN = Max, AEN=1, (unless otherwise noted) (Notes 1, 2, 3),

Parameter	Conditions	Channel	Min	Тур	Max	Units
Dark ADC count value	E _e = 0, ATIME=000b (100ms)	CH0 CH1	0 0		25 25	counts
ADC integration time step size	ATIME = 000b (100ms)		95	101	108	ms
ADC number of integration steps (Note 4)			1		6	steps
ADC counts per step	ATIME = 000b (100ms)		0		37888	counts
ADC count value	ATIME = 101b (600ms)		0		65535	counts
	White light (Note 2) $E_e = 4.98 \ \mu W/cm^2$ ATIME = 000b (100 ms)	CH0 CH1	25500	30000 4996	34500	counts
ADC count value	$\lambda_p = 850 \text{ nm (Note 3)}$ $E_e = 5.62 \ \mu\text{W/cm}^2$, ATIME = 000b (100 ms)	CH0 CH1	25500	30000 19522	34500	counts
ADC count value	White light (Note 2)		0.116	0.166	0.216	
ratio: CH1/CH0	$\lambda_p = 850 \text{ nm}$ (Note 3)		0.456	0.652	0.848	
R _e	White light (Note 2) ATIME = 000b (100 ms)	CH0 CH1		6024 1003		counts/
Irradiance responsivity	λ _p = 850 nm (Note 3) ATIME = 000b (100 ms)	CH0 CH1		5338 3474		(µW/cm ²)
Noise (Note 4)	White light (Note 2) $E_e = 4.98 \ \mu W/cm^2$ ATIME = 000b (100 ms)	СНО		1	2	1 standard deviation
Gain scaling, relative to 1× gain setting	AGAIN = Low AGAIN = Med AGAIN = High AGAIN = Max			1 25 428 9876		×

Notes:

1. Optical measurements are made using small-angle incident radiation from light-emitting diode optical sources. Visible white LEDs and infrared 850 nm LEDs are used for final product testing for compatibility with high-volume production

2. The white LED irradiance is supplied by a white light-emitting diode with a nominal color temperature of 4000 K.

3. The 850 nm irradiance is supplied by a GaAs light-emitting diode with the following typical characteristics: peak wavelength $\lambda_p = 850$ nm and spectral halfwidth $\Delta\lambda_{1/2} = 42$ nm.

4. Parameter ensured by design and is not 100% tested.



Timing Characteristics

The timing characteristics of TSL2591 are given below.

Figure TSL2591 – 10: AC Electrical Characteristics, V_{DD} = 3 V, T_A = 25°C (unless otherwise noted)

Parameter†	Description	Min	Тур	Max	Units
f _(SCL)	Clock frequency (I ² C only)	0		400	kHz
t _(BUF)	Bus free time between start and stop condition	1.3			μs
t _(HDSTA)	Hold time after (repeated) start condition. After this period, the first clock is generated.	0.6			μs
t _(SUSTA)	Repeated start condition setup time	0.6			μs
t _(SUSTO)	t _(SUSTO) Stop condition setup time				μs
t _(HDDAT)	Data hold time	0			μs
t _(SUDAT)	Data setup time	100			ns
t _(LOW)	SCL clock low period	1.3			μs
t _(HIGH)	SCL clock high period	0.6			μs
t _F	t _F Clock/data fall time			300	ns
t _R	Clock/data rise time			300	ns
C _i	Input pin capacitance			10	pF

† Specified by design and characterization; not production tested.

Timing Diagrams

Figure TSL2591 – 11: Parameter Measurement Information





Typical Operating Characteristics

Figure TSL2591 – 12: Spectral Responsivity

Spectral Responsivity: Two channel response allows for tunable illuminance (lux) calculation regardless of transmissivity of glass.



Figure TSL2591 – 13: White Normalized Responsivity vs. Angular Displacement

White LED Angular Response: Near cosine angular response for broadband white light sources.





Figure TSL2591 – 14: Normalized I_{DD} vs. V_{DD} and Temperature

I_{DD} **vs. V**_{DD} **vs. Temp:** Effect of supply voltage and temperature on active current.



Figure TSL2591 – 15: Response to White LED vs. Temperature



White LED Response v Temp: Effect of temperature on the device response for a broadband white light source.



Register Description

The device is controlled and monitored by registers accessed through the I²C serial interface. These registers provide for a variety of control functions and can be read to determine results of the ADC conversions. The register set is summarized in Figure TSL2591 - 16.

Figure TSL2591 – 16: Register Description

Address	Register Name	R/W	Register Function	Reset Value
	COMMAND	W	Specifies Register Address	0x00
0x00	ENABLE	R/W	Enables states and interrupts	0x00
0x01	CONFIG	R/W	ALS gain and integration time configuration	0x00
0x04	AILTL	R/W	ALS interrupt low threshold low byte	0x00
0x05	AILTH	R/W	ALS interrupt low threshold high byte	0x00
0x06	AIHTL	R/W	ALS interrupt high threshold low byte	0x00
0x07	AIHTH	R/W	ALS interrupt high threshold high byte	0x00
0x08	NPAILTL	R/W	No Persist ALS interrupt low threshold low byte	0x00
0x09	NPAILTH R/W No Persist ALS interrupt low threshold hig		No Persist ALS interrupt low threshold high byte	0x00
0x0A	NPAIHTL	R/W	No Persist ALS interrupt high threshold low byte	0x00
0x0B	NPAIHTH	R/W	No Persist ALS interrupt high threshold high byte	0x00
0x0C	PERSIST	R/W	Interrupt persistence filter	0x00
0x11	PID	R	Package ID	
0x12	ID	R	Device ID	ID
0x13	STATUS	R	Device status	0x00
0x14	CODATAL	R	CH0 ADC low data byte	0x00
0x15	CODATAH	R	CH0 ADC high data byte	0x00
0x16	C1DATAL	R	CH1 ADC low data byte	0x00
0x17	C1DATAH	R	CH1 ADC high data byte	0x00

Note: JGS-Stopped here.



Command Register

The COMMAND register specifies the address of the target register for future read and write operations, as well as issues special function commands.

7	6	5	4	3	2	1	0
CMD	TRANS	ACTION			ADDR/SF		

Fields	Bits	Description				
CMD	7	Select Command Register. Must write as 1 when addressing COMMAND register.				
		Select type of transa	ction to follow in subsequent data transfers			
		FIELD VALUE	DESCRIPTION			
		00	Reserved - Do not use			
TRANSACTION	6:5	01	Normal Operation			
		10	Reserved – Do not use			
		11	Special Function – See description below			
		type, see above, this command or selects subsequent read and	I function field. Depending on the transaction field either specifies a special function the specific control-status-data register for d write transactions. The field values listed special function commands. DESCRIPTION			
		00100	Interrupt set – forces an interrupt			
	4:0	00110	Clears ALS interrupt			
ADDR/SF		00111	Clears ALS and no persist ALS interrupt			
		01010	Clears no persist ALS interrupt			
		other	Reserved – Do not write			
		The interrupt set special function command sets the interrupt bits in the status register (0x13). For the interrupt to be visible on the INT pin, one of the interrupt enable bits in the enable register (0x00) must be asserted. The interrupt set special function must be cleared with an interrupt clear special function. The ALS interrupt clear special functions clear any pending interrupt(s) and are self-clearing.				



Enable Register (0x00)

The ENABLE register is used to power the device on/off, enable functions and interrupts.

7	6	5	4	3	2	1	0
NPIEN	SAI	Reserved	AIEN	Reserved		AEN	PON

Fields	Bits	Description		
NPIEN	7	No Persist Interrupt Enable. When asserted NP Threshold conditions will generate an interrupt, bypassing the persist filter.		
SAI	6	Sleep after interrupt. When asserted, the device will power down at the end of an ALS cycle if an interrupt has been generated.		
Reserved	5	Reserved. Write as 0.		
AIEN	4	ALS Interrupt Enable. When asserted permits ALS interrupts to be generated, subject to the persist filter.		
Reserved	3:2	Reserved. Write as 0.		
AEN	1	ALS Enable. This field activates ALS function. Writing a one activates the ALS. Writing a zero disables the ALS.		
PON	0	Power ON. This field activates the internal oscillator to permit the timers and ADC channels to operate. Writing a one activates the oscillator. Writing a zero disables the oscillator.		



Control Register (0x01)

The CONTROL register is used to configure the ALS gain and integration time. In addition, a system reset is provided. Upon power up, the CONTROL register resets to 0x00.

7	6	5	4	3	2	1	0
SRESET	Reserved	AG	AIN	Reserved		ATIME	

Fields	Bits		Description				
SRESET	7		en asserted, the device will re RESET is self-clearing.	eset equivalent to a			
Reserved	6	Reserved. Write a	s 0.				
		ALS gain sets the photodiode chan	gain of the internal integratic nels.	on amplifiers for both			
		FIELD VALUE	DESCRIPT	TION			
AGAIN	5:4	00	Low gain mode				
		01	Medium gain mode				
		10	High gain mode				
		11	Maximum gain mode				
Reserved	3	Reserved. Write as 0.					
			ALS time sets the internal ADC integration time for both photodiode channels.				
		FIELD VALUE	INTEGRATION TIME	MAX COUNT			
		000	100 ms	37888			
ATIME	2:0	001	200 ms	65535			
		010	300 ms	65535			
		011	400 ms	65535			
		100	500 ms	65535			
		101	600 ms	65535			



ALS Interrupt Threshold Register (0x04 – 0x0B)

The ALS interrupt threshold registers provide the values to be used as the high and low trigger points for the comparison function for interrupt generation. If CODATA crosses below the low threshold specified, or above the higher threshold, an interrupt is asserted on the interrupt pin.

If the C0DATA exceeds the persist thresholds (registers: 0x04 – 0x07) for the number of persist cycles configured in the PERSIST register an interrupt will be triggered. If the C0DATA exceeds the no-persist thresholds (registers: 0x08 – 0x0B) an interrupt will be triggered immediately following the end of the current integration.

Note that while the interrupt is observable in the STATUS register (0x13), it is visible only on the INT pin when AIEN or NPIEN are enabled in the ENABLE register (0x00).

Upon power up, the interrupt threshold registers default to 0x00.

Register	Address	Bits	Description
AILTL	0x04	7:0	ALS low threshold lower byte
AILTH	0x05	7:0	ALS low threshold upper byte
AIHTL	0x06	7:0	ALS high threshold lower byte
AIHTH	0x07	7:0	ALS high threshold upper byte
NPAILTL	0x08	7:0	No Persist ALS low threshold lower byte
NPAILTH	0x09	7:0	No Persist ALS low threshold upper byte
NPAIHTL	0x0A	7:0	No Persist ALS high threshold lower byte
NPAIHTH	0x0B	7:0	No Persist ALS high threshold upper byte



PERSIST Register (0x0C)

The Interrupt persistence filter sets the number of consecutive out-of-range ALS cycles necessary to generate an interrupt. Out-of-range is determined by comparing CODATA (0x14 and 0x15) to the interrupt threshold registers (0x04 - 0x07). Note that the no-persist ALS interrupt is not affected by the interrupt persistence filter. Upon power up, the interrupt persistence filter register resets to 0x00.

7	6	5	4	3	2	1	0
	Rese	erved			AP	ERS	

Field	Bits	Description				
Reserved	7:4	Reserved. Write as 0.				
		ALS interrupt persistence	e filter			
		FIELD VALUE	PERSISTENCE			
		0000	Every ALS cycle generates an interrupt			
		0001	Any value outside of threshold range			
		0010	2 consecutive values out of range			
		0011	3 consecutive values out of range			
		0100	5 consecutive values out of range			
		0101	10 consecutive values out of range			
APERS	3:0	0110	15 consecutive values out of range			
AFENJ	5:0	0111	20 consecutive values out of range			
		1000	25 consecutive values out of range			
		1001	30 consecutive values out of range			
		1010	35 consecutive values out of range			
		1011	40 consecutive values out of range			
		1100	45 consecutive values out of range			
		1101	50 consecutive values out of range			
		1110	55 consecutive values out of range			
		1111	60 consecutive values out of range			



PID Register (0x11)

The PID register provides an identification of the devices package. This register is a read-only register whose value never changes.

7	6	5	4	3	2	1	0
Reser	ved	PACK	AGEID		Rese	rved	

Field	Bits	Description
Reserved	7:6	Reserved.
PID	5:4	Package Identification = 00
Reserved	3:0	Reserved.

ID Register (I0x12)			The ID register provides the device identification. This register is a read-only register whose value never changes.				
7	6	5	4	3	2	1	0
				D			

Field	Bits	Description
ID	7:0	Device Identification = 0x50

Status Register (0x13)

The Status Register provides the internal status of the device. This register is read only.

7	6	5	4	3	2	1	0	
Rese	erved	NPINTR	AINT		Reserved		AVALID	

Field	Bits	Description
Reserved	7:6	Reserved. Write at zero.
NPINTR	5	No-persist Interrupt. Indicates that the device has encountered a no-persist interrupt condition.
AINT	4	ALS Interrupt. Indicates that the device is asserting an ALS interrupt.
Reserved	3:1	Reserved.
AVALID	0	ALS Valid. Indicates that the ADC channels have completed an integration cycle since the AEN bit was asserted.



ALS Data Register (0x14 - 0x17)

ALS data is stored as two 16-bit values; one for each channel. When the lower byte of either channel is read, the upper byte of the same channel is latched into a shadow register. The shadow register ensures that both bytes are the result of the same ALS integration cycle, even if additional integration cycles occur between the lower byte and upper byte register readings.

Each channel independently operates the upper byte shadow register. So to minimize the potential for skew between CH0 and CH1 data, it is recommended to read all four ADC bytes in sequence. The simplest way to accomplish this is to perform a four-byte l²C read operation using the auto-increment protocol, which is set in the Command register TRANSACTION field.

Register	Address	Bits	Description
CODATAL	0x14	7:0	ALS CH0 data low byte
CODATAH	0x15	7:0	ALS CH0 data high byte
C1DATAL	0x16	7:0	ALS CH1 data low byte
C1DATAH	0x17	7:0	ALS CH1 data high byte



Application Information

Figure TSL2591 - 17 shows a typical hardware application circuit. A 1- μ F low-ESR decoupling capacitor should be placed as close as possible to the V_{DD} pin. V_{BUS} in this figure refers to the l²C bus voltage, which is equal to V_{DD}.

Figure TSL2591 – 17: Typical Application Hardware Circuit



The I²C signals and the Interrupt are open-drain outputs and require pull-up resistors. The pull-up resistor (RP) value is a function of the I²C bus speed, the I²C bus voltage, and the capacitive load. The ams EVM running at 400 kbps, uses 1.5-k Ω resistors. A 10-k Ω pull-up resistor (RPI) can be used for the interrupt line.



PCB Pad Layout

Suggested land pattern based on the IPC–7351B Generic Requirements for Surface Mount Design and Land Pattern Standard (2010) for the small outline no-lead (SON) package is shown in Figure TSL2591 - 18.

Figure TSL2591 – 18: Suggested FN Package PCB Layout (Top View)



Notes:

- 1. All linear dimensions are in millimeters.
- 2. This drawing is subject to change without notice.



Package Drawings and Markings

Figure TSL2591 – 19: FN Package – Dual Flat No-Lead Packaging Configuration



Notes:

- 1. All linear dimensions are in micrometers.
- 2. The die is centered within the package within a tolerence of $\pm 75\,\mu\text{m}.$
- 3. Package top surface is molded with an electrically non-conductive clear plastic compound having an index of refraction of 1.55.
- 4. Contact finish is copper alloy A194 with pre-plated NIPdAu lead finish.
- 5. This package contains no lead (Pb).
- 6. This drawing is subject to change without notice.



Mechanical Data

Figure TSL2591 – 20: FN Package Carrier Tape and Reel Information



Notes:

- 1. All linear dimensions are in millimeters. Dimension tolerance is \pm 0.10 mm unless otherwise noted.
- 2. The dimensions on this drawing are for illustrative purposes only. Dimensions of an actual carrier may vary slightly.
- 3. Symbols on drawing $A_{\rm O},\,B_{\rm O}$ and $K_{\rm O}$ are defined in ANSI EIA Standard 481-B 2001.
- 4. Each reel is 178 millimeters in diameter and contains 3500 parts.
- 5. ams packaging tape and reel conform to the requirements of EIA Standard 481 B.
- 6. In accordance with EIA Standard, device pin 1 is located next to the sprocket holes in the tape.
- 7. This drawing is subject to change without notice.



Soldering Information

The package has been tested and has demonstrated an ability to be reflow soldered to a PCB substrate.

The solder reflow profile describes the expected maximum heat exposure of components during the solder reflow process of product on a PCB. Temperature is measured on top of component. The components should be limited to a maximum of three passes through this solder reflow profile.

Figure TSL2591 – 21: Solder Reflow Profile

Parameter	Reference	Device
Average temperature gradient in preheating		2.5 °C/sec
Soak time	t _{soak}	2 to 3 minutes
Time above 217 °C (T1)	t ₁	Max 60 sec
Time above 230 °C (T2)	t ₂	Max 50 sec
Time above T _{peak} - 10 °C (T3)	t ₃	Max 10 sec
Peak temperature in reflow	T _{peak}	260 °C
Temperature gradient in cooling		Max -5 °C/sec

Figure TSL2591 – 22: Solder Reflow Profile Graph



Note: Not to scale - for reference only.



Storage Information

Moisture Sensitivity

Optical characteristics of the device can be adversely affected during the soldering process by the release and vaporization of moisture that has been previously absorbed into the package. To ensure the package contains the smallest amount of absorbed moisture possible, each device is baked prior to being dry packed for shipping.

Devices are dry packed in a sealed aluminized envelope called a moisture-barrier bag with silica gel to protect them from ambient moisture during shipping, handling, and storage before use.

Shelf Life

The calculated shelf life of the device in an unopened moisture barrier bag is 12 months from the date code on the bag when stored under the following conditions:

- Shelf Life: 12 months
- Ambient Temperature: < 40°C
- Relative Humidity: < 90%

Rebaking of the devices will be required if the devices exceed the 12 month shelf life or the Humidity Indicator Card shows that the devices were exposed to conditions beyond the allowable moisture region.

Floor Life

The FN package has been assigned a moisture sensitivity level of MSL 3. As a result, the floor life of devices removed from the moisture barrier bag is 168 hours from the time the bag was opened, provided that the devices are stored under the following conditions:

- Floor Life: 168 hours
- Ambient Temperature: < 30°C
- Relative Humidity: < 60%

If the floor life or the temperature/humidity conditions have been exceeded, the devices must be rebaked prior to solder reflow or dry packing.

Rebaking Instructions

When the shelf life or floor life limits have been exceeded, rebake at 50°C for 12 hours.



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